TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (U-MOSV)

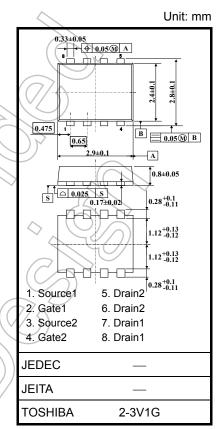
# **TPCP8303**

#### Lithium Ion Battery Applications Notebook PC Applications Portable Equipment Applications

- Low drain-source ON-resistance:  $R_{DS(ON)} = 41 \text{ m}\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 12 \text{ S}$  (typ.)
- Low leakage current:  $I_{DSS} = -10 \ \mu A \ (max) \ (V_{DS} = -20 \ V)$
- Enhancement mode:  $V_{th} = -0.3$  to -1.0 V ( $V_{DS} = -10$  V,  $I_D = -1$  mA)

## Absolute Maximum Ratings (Ta = 25°C) (Q1, Q2 Common)

Cha	racteristic	Symbol	Rating	Unit
Drain-source voltage	ge	V <sub>DSS</sub>	-20	$\gamma$
Drain-gate voltage	$(R_{GS} = 20 \text{ k}\Omega)$	V <sub>DGR</sub>	-20	(v)
Gate-source voltag	je	V <sub>GSS</sub>	±8	V
Drain current	DC (Note 1)	I <sub>D</sub>	-3.8	A
Dialiticulterit	Pulse (Note 1)	I <sub>DP</sub>	-20 -20 ±8	
Drain power dissipation	Single-device operation (Note 3a)	P <sub>D (1)</sub>	1.48	
(t = 5 s) (Note 2a)	Single-device value at dual operation (Note 3b)	P <sub>D</sub> (2)	1.23	NV
Drain power dissipation	Single-device operation (Note 3a)	PD (1)	0.58	
(t = 5 s) (Note 2b)	Single-device value at dual operation (Note 3b)	P <sub>D (2)</sub>		
Single-pulse avala	nche energy (Note 4)	EAS	18.8 🔇	mJ
Avalanche current		JAR	-3.8	A
Repetitive avalanc Single-device value	he energy e at dual operation (Note 2a, 3b, 5)	Ear	0.04	mJ
Channel temperatu	ire	T <sub>ch</sub>	( 150	°C
Storage temperatu	re range	T <sub>stg</sub>	-55 to 150	°C



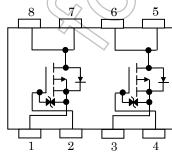
Weight: 0.017 g (typ.)

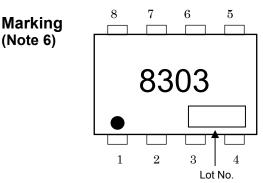
Note: For Notes 1 to 6, see the next page.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Handle with care.





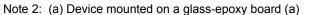


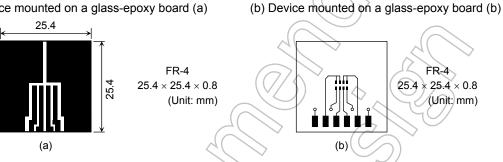
Start of commercial production 2009-05

#### **Thermal Characteristics**

Chara	Characteristic		Max	Unit	
Thermal resistance, channel to ambient (t = 5 s) (Note 2a)	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	84.5	- °C/W	
	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	101.6		
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	215.5	°C/W	
(t = 5 s) (Note 2b)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	347.2	C/W	

Note 1: Ensure that the channel temperature does not exceed 150°C.





- Note 3: a) The power dissipation and thermal resistance values shown are for a single device. (During single-device operation, power is applied to one device only.)
  - b) The power dissipation and thermal resistance values shown are for a single device. (During dual operation, power is applied to both devices evenly.).
- Note 4:  $V_{DD} = -16 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}$  (initial), L = 1 mH,  $R_G = 1 \Omega$ ,  $I_{AR} = -3.8 \text{ A}$
- Note 5: Repetitive rating: pulse width limited by maximum channel temperature
- Note 6: on the lower left of the marking indicates Pin 1.

\* Weekly code (three digits);

Week of manufacture

(01 for the first week of the year, continuing up to 52 or 53)

Year of manufacture (The last digit of the year)

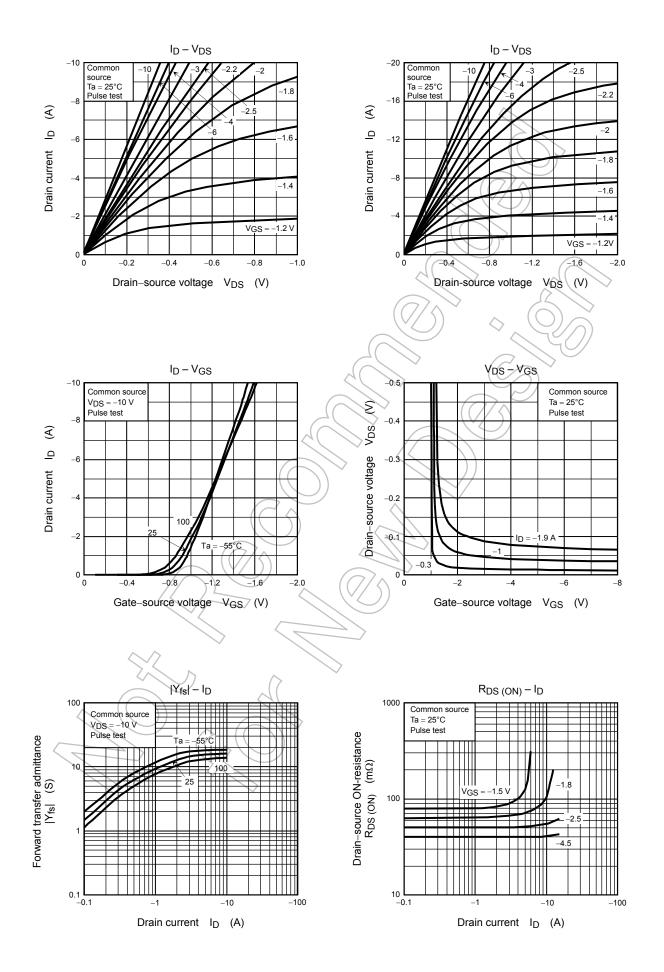
#### Electrical Characteristics (Ta = 25°C)

Ch	aracteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cui	rent	I <sub>GSS</sub>	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±1	μA
Drain cutoff curre	ent	IDSS	$V_{DS} = -20 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		_	-10	μA
Drain-source breakdown voltage		V (BR) DSS	$I_D = -10 \text{ mA}, \text{ V}_{GS} = 0 \text{ V}$	-20	_		v
		V (BR) DSX	$I_D = -10 \text{ mA}, V_{GS} = 8 \text{ V}$	12			v
Gate threshold ve	oltage	V <sub>th</sub>	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -1 \text{ mA}$	-0.3	$\langle \rangle$	-1.0	V
		R <sub>DS (ON)</sub>	$V_{GS} = -1.5 \text{ V}, \text{ I}_{D} = -0.3 \text{ A}$	Y,	85	144	
Drain-source ON-resistance		R <sub>DS (ON)</sub>	$V_{GS} = -1.8 V, I_D = -1.0 A$	74	66	90	
Drain-source ON	resistance	R <sub>DS (ON)</sub>	$V_{GS} = -2.5 \text{ V}, \text{ I}_{D} = -1.9 \text{ A}$	7	52	60	mΩ
		R <sub>DS (ON)</sub>	$V_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -1.9 \text{ A}$	> -	41	46	
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -1.9 \text{ A}$	6	12	_	S
Input capacitance		C <sub>iss</sub>		_	640	<u>/-</u>	
Reverse transfer	capacitance	C <sub>rss</sub>	$V_{DS} = -10 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$	- /	100	$\geq$	pF
Output capacitan	се	C <sub>oss</sub>	(775)	-6	140	$\geq -$	
Switching time	Rise time	tr	$V_{GS} = -1.9 \text{ A}$	V	12	) _	
	Turn-on time	t <sub>on</sub>			20		ns
	Fall time	t <sub>f</sub>	×××   " + m o d V <sub>DD</sub> ≈ −10 V		43	_	
	Turn-off time	toff	Duty ≤ 1%, t <sub>w</sub> = 10 μs	_	138		
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \approx -16 \text{ V}, \text{ V}_{GS} = -5 \text{ V},$		10		
Gate-source charge1		Q <sub>gs1</sub>	$I_{\rm D} = -3.8 \rm{A}$	_	1.6	_	nC
Gate-drain ("Mille	er") charge	Q <sub>gd</sub>		_	2.1		

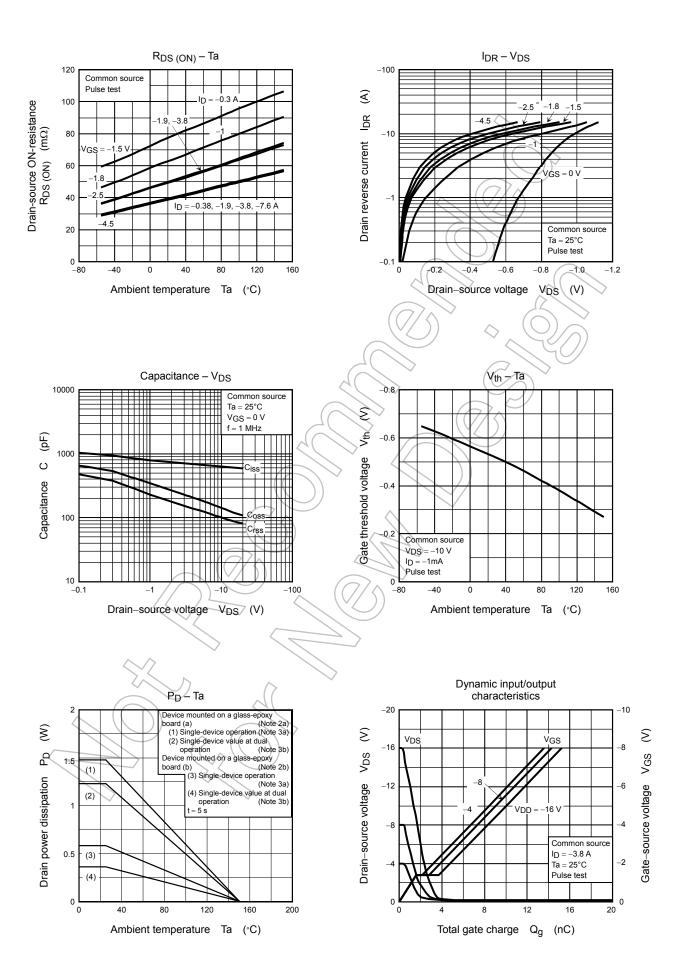
#### Source-Drain Ratings and Characteristics (Ta = 25°C)

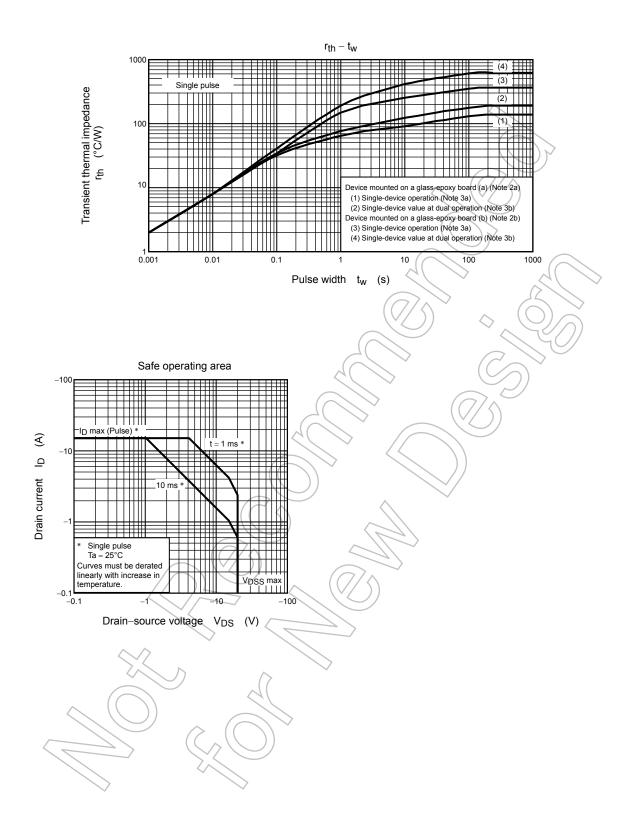
Characteris	tic	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	DRP		_	_	-15.2	А
Forward voltage (diode)	$\searrow$	VDSF	$I_{DR} = -3.8 \text{ A}, V_{GS} = 0 \text{ V}$			1.2	V

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